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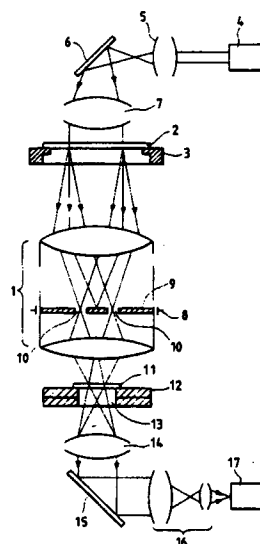
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(54) **Apparatus for evaluating a lens.**

(57) A first reticle (2) is located at an object position of a lens (1) to be evaluated. The first reticle is formed with a first diffraction grating. A stage (3) supports the first reticle. A coherent light source (4) illuminates a whole region of the first diffraction grating. A spatial filter (9) blocks a 0-order component of diffraction light from the first diffraction grating. A second reticle (11) is located at an image position of the lens and is formed with a second diffraction grating. A stage (12) moves the second reticle within a projection range of the lens (1). Interference fringes are formed on the second reticle by re-diffraction by the lens. Moire fringes are caused by the second diffraction grating and the interference fringes. The moire fringes are observed.

FIG. 1





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EUROPEAN SEARCH REPORT

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DOCUMENTS CONSIDERED TO BE RELEVANT

Category	Citation of document with indication, where appropriate, of relevant passages	Relevant to claim	CLASSIFICATION OF THE APPLICATION (Int. Cl.5)
X Y	US-A-2 818 775 (F. C. ULLRICH) * column 2, line 55 - column 3, line 53; figures 1-3 * ---	1 1-3	G01M11/02
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A	GB-A-1 527 595 (SIRA INSTITUTE LIMITED) * the whole document * -----	1,3	
The present search report has been drawn up for all claims			
Place of search THE HAGUE		Date of completion of the search 03 SEPTEMBER 1992	Examiner VAN ASSCHE P.O.
CATEGORY OF CITED DOCUMENTS X : particularly relevant if taken alone Y : particularly relevant if combined with another document of the same category A : technological background O : non-written disclosure P : intermediate document T : theory or principle underlying the invention E : earlier patent document, but published on, or after the filing date D : document cited in the application L : document cited for other reasons & : member of the same patent family, corresponding document			